

<b>Notice of References Cited</b>	Application/Control No. 09/534,204	Applicant(s)/Patent Under Reexamination IMAI ET AL.	
	Examiner Shun Lee	Art Unit 2884	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-5,483,071 A1	01-1996	Oikawa et al.	250/370.09
	B	US-			
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	D	US-			
	E	US-			
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	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

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**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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